

HORIBA

NETZSCH

PARTICLE CHARACTERIZATION AND NANOTECHNOLOGY SEMINAR THURSDAY, OCTOBER 23RD, 2008

NETZSCH Fine Particle Technology and HORIBA Instruments, Inc. present a seminar on nanotechnology with speakers who are acknowledged experts in the field. Emphasis will be on applications, problem solving and new developments.

Program Agenda



Held at:
HORIBA Technology Center
3265 Scott Boulevard
Santa Clara, California
(888) 246-7422

- 8:15 Seminar Registration
- 8:30 Micro-contamination; Its Effects on Micro-electronics and Potential Effects on Nano-technology
Brian J. Grenon, SPIE Photomask Working Group
- 9:10 Synthesis and Applications of Carbon Nanotubes and Nanofibers
Brett Cruden, NASA Ames Research Center
- 9:45 Nano Grinding in Agitator Bead Mills
Holger Spranger, NETZSCH Fine Particle Technology
- 10:20 Break
- 10:40 Particle Size Method Development and Validation Support of NanoCrystal™ Colloidal Dispersion Formulation Characterization
Joost Strasters, Elan Pharmaceuticals
- 11:10 Nanotechnology, Nanoparticles and Characterization Techniques
Mark Bumiller, HORIBA Instruments, Inc.
- 11:45 Lunch
- 1:00 Instrument Demonstrations (optional)
For people interested in observing instruments in action, a range of analyzers will be on hand.

There is no fee for this seminar, but reservations are required.

RSVP by October 15, 2008

Contact Carol Madden at (800) 446-7422 x 1133

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